

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

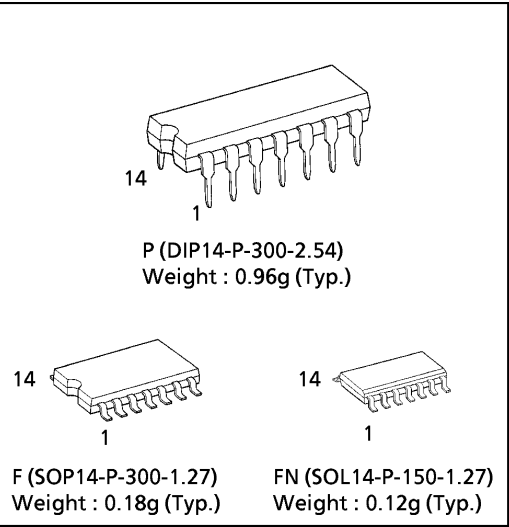
TC4081BP, TC4081BF, TC4081BFN

TC4081B QUAD 2 INPUT AND GATE

TC4081B is positive logic AND gates with two inputs respectively.

Since all the outputs of these gates are equipped with the buffer circuits of inverters, the input/output propagation characteristic has been improved and variation of propagation time caused by increase of load capacity is kept minimum.

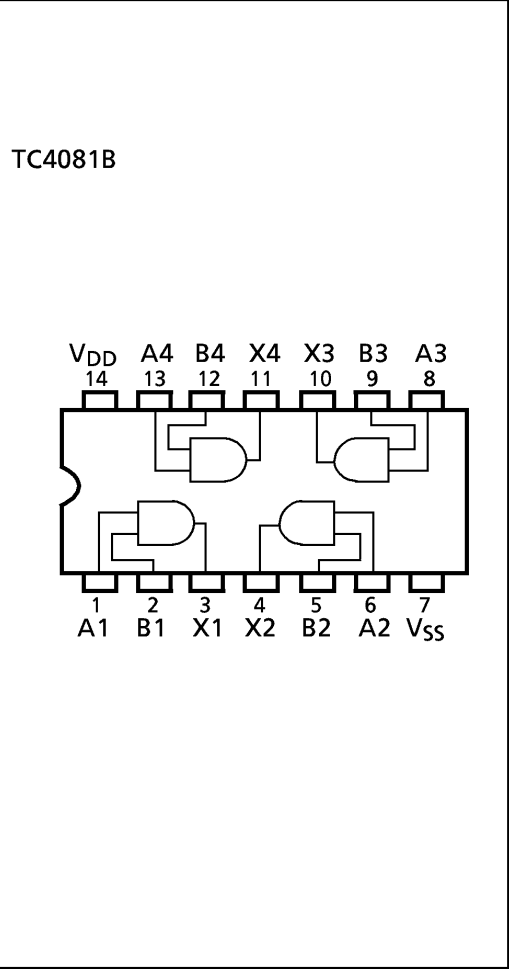
(Note) The JEDEC SOP (FN) is not available in Japan.



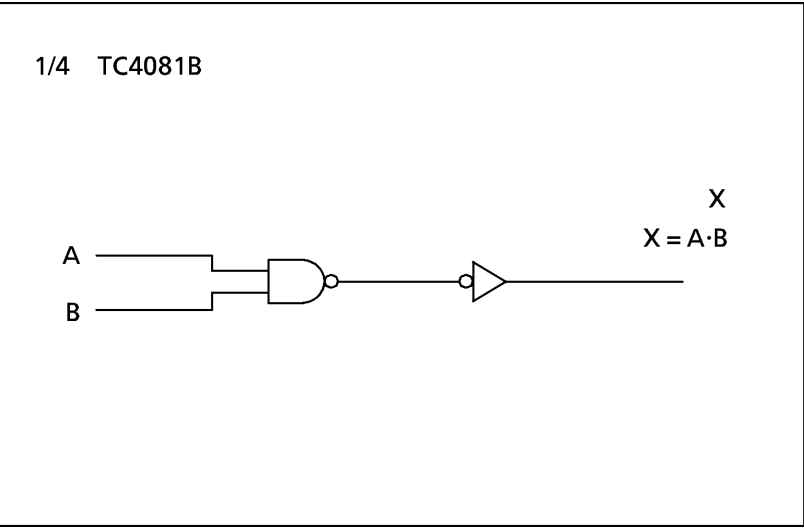
MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V_{DD}	$V_{SS} - 0.5 \sim V_{SS} + 20$	V
Input Voltage	V_{IN}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
Output Voltage	V_{OUT}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
DC Input Current	I_{IN}	± 10	mA
Power Dissipation	P_D	300 (DIP) / 180 (SOIC)	mW
Operating Temperature Range	T_{ope}	$-40 \sim 85$	°C
Storage Temperature Range	T_{stg}	$-65 \sim 150$	°C

PIN ASSIGNMENT (TOP VIEW)



LOGIC DIAGRAM



RECOMMENDED OPERATING CONDITIONS ($V_{SS} = 0V$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	V_{DD}		3	—	18	V
Input Voltage	V_{IN}		0	—	V_{DD}	V

STATIC ELECTRICAL CHARACTERISTICS ($V_{SS} = 0V$)

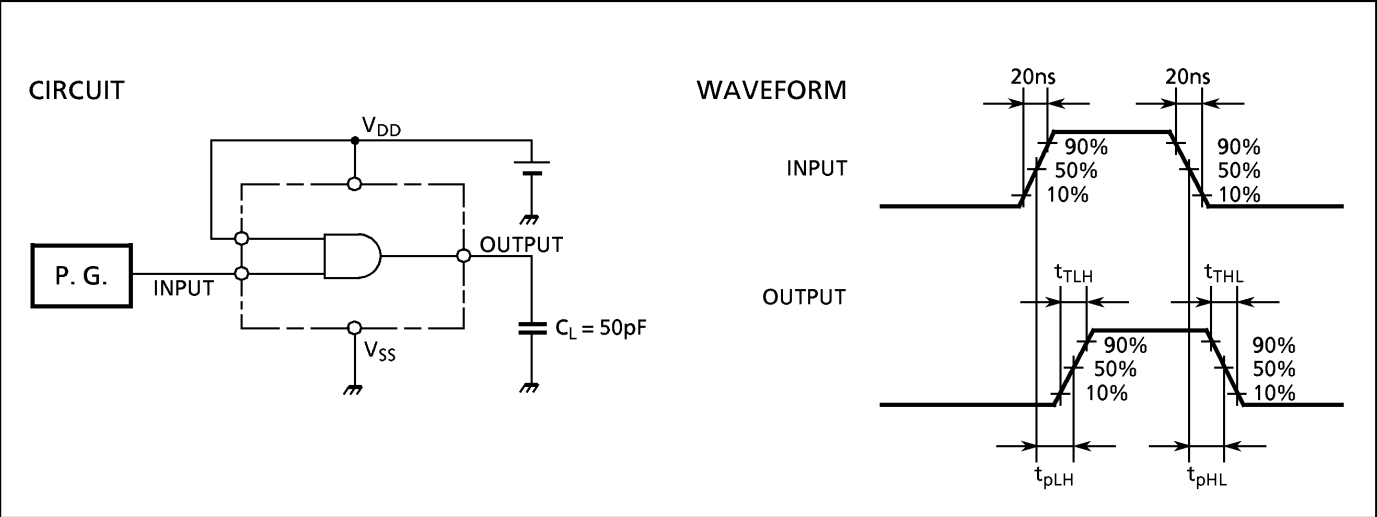
CHARACTERISTIC	SYM-BOL	TEST CONDITION	V_{DD} (V)	- 40°C		25°C			85°C		UNIT
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
High-Level Output Voltage	V_{OH}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V
			10	9.95	—	9.95	10.00	—	9.95	—	
			15	14.95	—	14.95	15.00	—	14.95	—	
Low-Level Output Voltage	V_{OL}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V
			10	—	0.05	—	0.00	0.05	—	0.05	
			15	—	0.05	—	0.00	0.05	—	0.05	
Output High Current	I_{OH}	$V_{OH} = 4.6V$	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA
		$V_{OH} = 2.5V$	5	-2.50	—	-2.10	-4.0	—	-1.70	—	
		$V_{OH} = 9.5V$	10	-1.50	—	-1.30	-2.2	—	-1.10	—	
		$V_{OH} = 13.5V$	15	-4.00	—	-3.40	-9.0	—	-2.80	—	
		$V_{IN} = V_{DD}$									
Output Low Current	I_{OL}	$V_{OL} = 0.4V$	5	0.61	—	0.51	1.2	—	0.42	—	mA
		$V_{OL} = 0.5V$	10	1.50	—	1.30	3.2	—	1.10	—	
		$V_{OL} = 1.5V$	15	4.00	—	3.40	12.0	—	2.80	—	
		$V_{IN} = V_{SS}, V_{DD}$									
Input High Voltage	V_{IH}	$V_{OUT} = 0.5V, 4.5V$	5	3.5	—	3.5	2.75	—	3.5	—	V
		$V_{OUT} = 1.0V, 9.0V$	10	7.0	—	7.0	5.50	—	7.0	—	
		$V_{OUT} = 1.5V, 13.5V$	15	11.0	—	11.0	8.25	—	11.0	—	
		$ I_{OUT} < 1\mu A$									
Input Low Voltage	V_{IL}	$V_{OUT} = 0.5V, 4.5V$	5	—	1.5	—	2.25	1.5	—	1.5	V
		$V_{OUT} = 1.0V, 9.0V$	10	—	3.0	—	4.50	3.0	—	3.0	
		$V_{OUT} = 1.5V, 13.5V$	15	—	4.0	—	6.75	4.0	—	4.0	
		$ I_{OUT} < 1\mu A$									
Input Current	"H" Level	I_{IH}	$V_{IH} = 18V$	18	—	0.1	—	10^{-5}	0.1	—	μA
	"L" Level	I_{IL}	$V_{IL} = 0V$	18	—	-0.1	—	-10^{-5}	-0.1	—	
Quiescent Supply Current	I_{DD}	$V_{IN} = V_{SS}, V_{DD}^*$	5	—	0.25	—	0.001	0.25	—	7.5	μA
			10	—	0.50	—	0.001	0.50	—	15.0	
			15	—	1.00	—	0.002	1.00	—	30.0	

* All valid input combinations.

DYNAMIC ELECTRICAL CHARACTERISTICS (Ta = 25°C, Vss = 0V, CL = 50pF)

CHARACTERISTIC	SYMBOL	TEST CONDITION	VDD(V)	MIN.	TYP.	MAX.	UNIT
Output Transition Time	tTLH		5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output Transition Time	tTHL		5	—	70	200	
			10	—	35	100	
			15	—	30	80	
Propagation Delay Time	tPLH		5	—	65	200	
			10	—	30	100	
			15	—	25	80	
Propagation Delay Time	tPHL		5	—	65	200	
			10	—	30	100	
			15	—	25	80	
Input Capacitance	CIN			—	5	7.5	pF

CIRCUITS AND WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS



DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

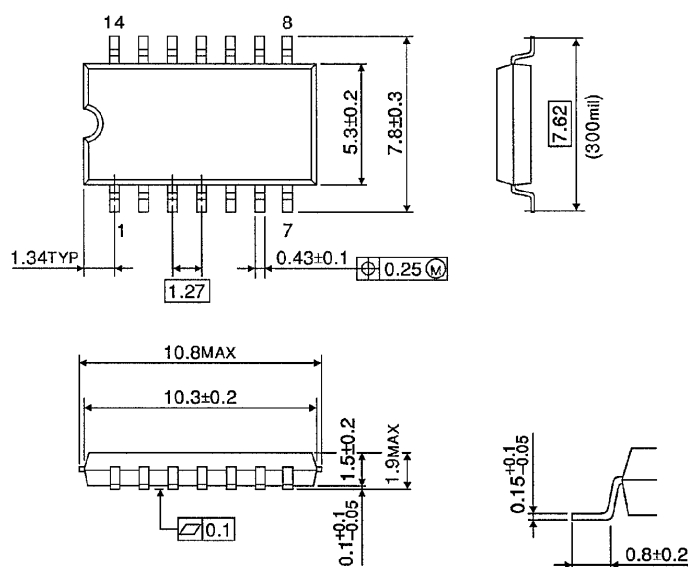
Unit in mm



Weight : 0.96g (Typ.)

SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm

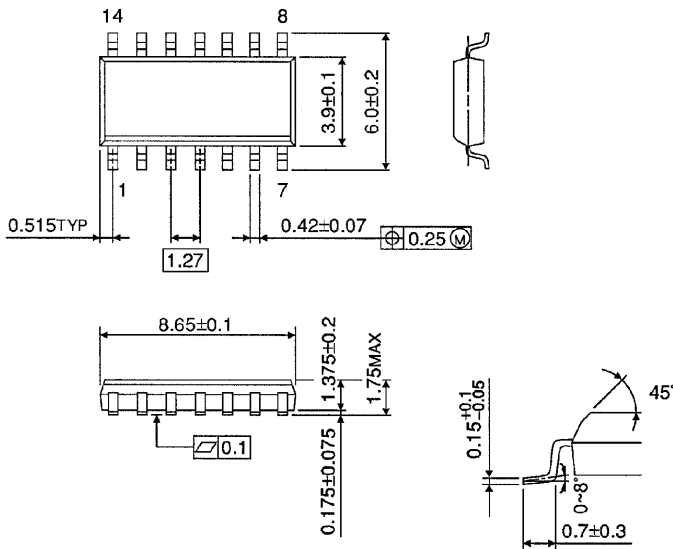


Weight : 0.18g (Typ.)

SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150 -1.27)

Unit in mm

(Note) This package is not available in Japan.



Weight : 0.12g (Typ.)

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